

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/822,884	YIP ET AL.	
Examiner		Art Unit	Tanh Q. Nguyen	

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*	B	US-2004/0113129 B1	06-2004	Waggoner et al.	252/500
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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